Unit: mm

TOSHIBA Diode Silicon Epitaxial Planar Diode

1SS398

High Voltage, High Speed Switching Applications

 $\begin{array}{ll} \bullet & \text{Low forward voltage} & : V_F = 1.0 \text{V (typ.)} \\ \bullet & \text{High voltage} & : V_R = 400 \text{V (min)} \\ \bullet & \text{Fast reverse recovery time: } t_{rr} = 0.5 \mu \text{s (typ.)} \\ \bullet & \text{Small total capacitance} & : C_T = 2.5 p \text{F (typ.)} \\ \end{array}$

• Small package : SC-59

Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit
Maximum (peak) reverse Voltage	V_{RM}	420	V
Reverse voltage	V _R	400	V
Maximum (peak) forward current	I _{FM}	300 *	mA
Average forward current	Io	100 *	mA
Surge current (10ms)	I _{FSM}	2 *	Α
Power dissipation	Р	150	mW
Junction temperature	Tj	125	°C
Storage temperature range	T _{stg}	-55~125	°C

^{* :} Unit rating. Total rating = unit rating × 0.7

1. ANODE 1 2. CATHODE 2 S-MINI 3. ANODE 2, CATHODE 1 JEDEC TO-236MOD EIAJ SC-59 TOSHIBA 1-3G1G

Weight: 0.012g

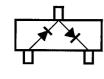
Electrical Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Forward voltage	V _{F (1)}	_	I _F = 10mA	_	0.8	_	V
	V _{F (2)}	_	I _F = 100mA	_	1.0	1.3	
Reverse current	I _{R (1)}	_	V _R = 300V	1	_	0.1	μΑ
	I _{R (2)}	_	V _R = 400V	_	_	1.0	
Total capacitance	C _T	_	$V_R = 0$, $f = 1MH_Z$	_	2.5	5.0	pF
Reverse recovery time	t _{rr}	_	$I_F = 10\text{mA}$ (Fig.1)	_	0.5	_	μs

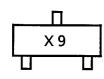
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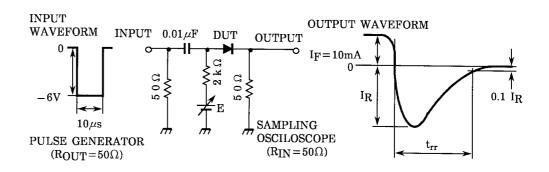
Equivalent Circuit (Top View)

Fig.1 Reverse Recovery Time (t_{rr}) Test Circuit

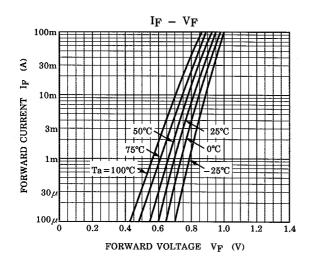


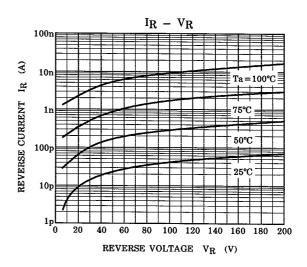


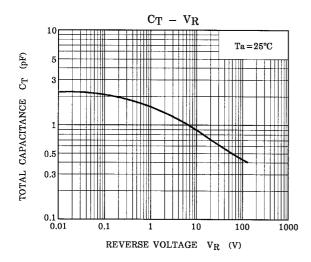


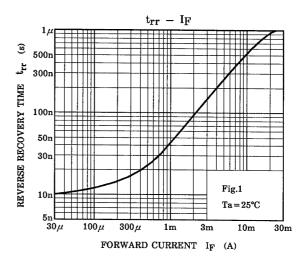


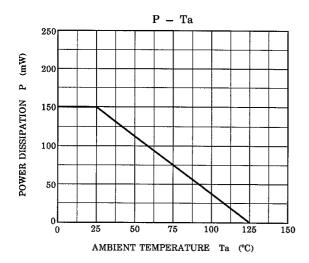
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